

## 9A, 900V N-CHANNEL MOSFET

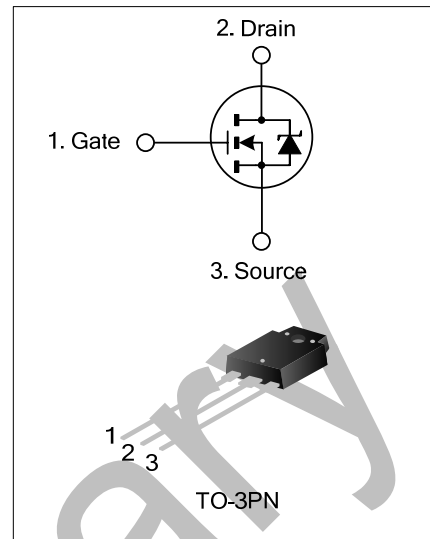
### DESCRIPTION

SVF9N90PN is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ structure VDMOS technology. The improved planar stripe cell and the improved guard ring terminal have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

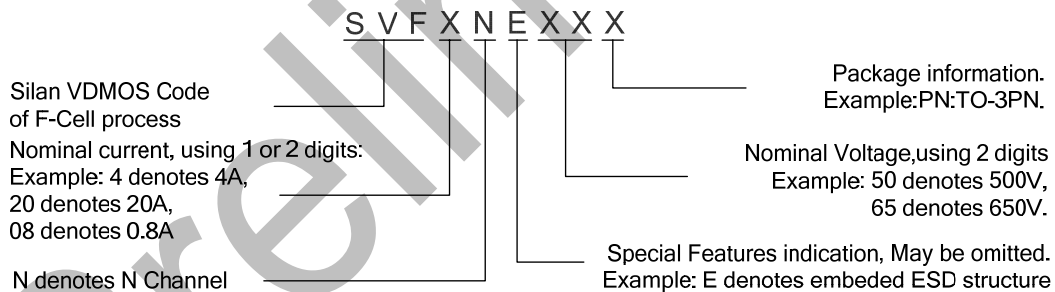
These devices are widely used in AC-DC power suppliers, DC-DC converters and H-bridge PWM motor drivers.

### FEATURES

- \* 9A, 900V,  $R_{DS(on)}(typ.)=1.10\Omega@V_{GS}=10V$
- \* Low gate charge
- \* Low Crss
- \* Fast switching
- \* Improved dv/dt capability



### NOMENCLATURE



### ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SVF9N90PN	TO-3PN	9N90	Pb free	Tube

### ABSOLUTE MAXIMUM RATINGS (unless otherwise noted, $T_C=25^{\circ}\text{C}$ )

Characteristics	Symbol	Ratings	Unit	
Drain-Source Voltage	$V_{DS}$	900	V	
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V	
Drain Current	$I_D$	$T_C=25^{\circ}\text{C}$	9.0	A
		$T_C=100^{\circ}\text{C}$	5.7	
Drain Current Pulsed	$I_{DM}$	36.0	A	
Power Dissipation ( $T_C=25^{\circ}\text{C}$ ) -Derate above $25^{\circ}\text{C}$	$P_D$	280	W	
		2.22	W/ $^{\circ}\text{C}$	
Single Pulsed Avalanche Energy (Note 1)	$E_{AS}$	890	mJ	
Operation Junction Temperature Range	$T_J$	$-55\sim+150$	$^{\circ}\text{C}$	
Storage Temperature Range	$T_{stg}$	$-55\sim+150$	$^{\circ}\text{C}$	

### THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.45	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	40	$^{\circ}\text{C}/\text{W}$

### ELECTRICAL CHARACTERISTICS (unless otherwise noted, $T_C=25^{\circ}\text{C}$ )

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	$B_{V_{DS}}$	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	900	--	--	V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS}=900\text{V}, V_{GS}=0\text{V}$	--	--	10	$\mu\text{A}$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 25\text{V}, V_{DS}=0\text{V}$	--	--	$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu\text{A}$	2.0	--	4.0	V
On State Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=4.5\text{A}$	--	1.10	1.4	$\Omega$
Input Capacitance	$C_{iss}$	$V_{DS}=25\text{V}, V_{GS}=0\text{V},$ $f=1.0\text{MHz}$	--	2000	--	pF
Output Capacitance	$C_{oss}$		--	160	--	
Reverse Transfer Capacitance	$C_{rss}$		--	12	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=450\text{V}, R_G=25\Omega,$ $I_D=9.0\text{A}$  (Note2,3)	--	45	--	ns
Turn-on Rise Time	$t_r$		--	115	--	
Turn-off Delay Time	$t_{d(off)}$		--	80	--	
Turn-off Fall Time	$t_f$		--	70	--	
Total Gate Charge	$Q_g$	$V_{DD}=720\text{V}, V_{GS}=10\text{V},$ $I_D=9.0\text{A}$  (Note 2,3)	--	40	--	nC
Gate-Source Charge	$Q_{gs}$		--	12	--	
Gate-Drain Charge	$Q_{gd}$		--	16	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

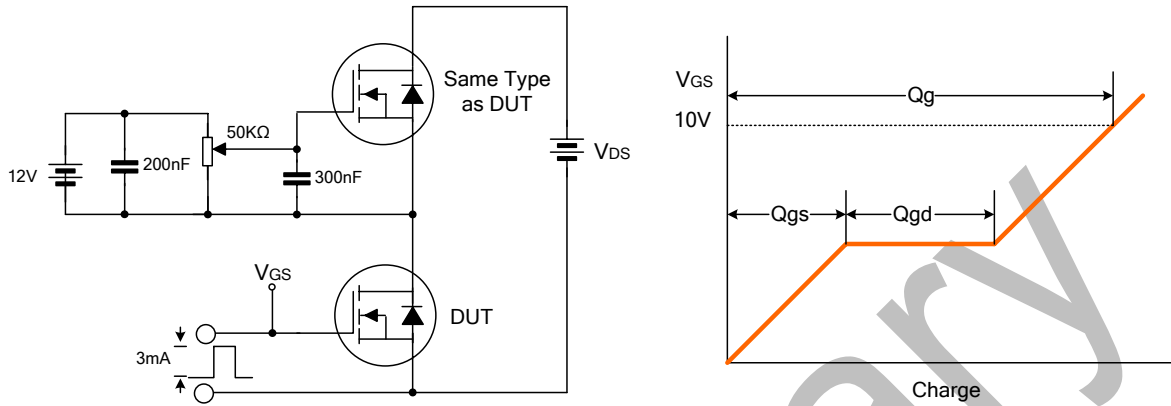
Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Source Current	$I_S$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	9.0	A
Pulsed Source Current	$I_{SM}$		--	--	36.0	
Diode Forward Voltage	$V_{SD}$	$I_S=9.0A, V_{GS}=0V$	--	--	1.4	V
Reverse Recovery Time	$T_{rr}$	$I_S=9.0A, V_{GS}=0V,$ $dI_F/dt=100A/\mu S$ (Note2)	--	540	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	6.1	--	$\mu C$

### Notes:

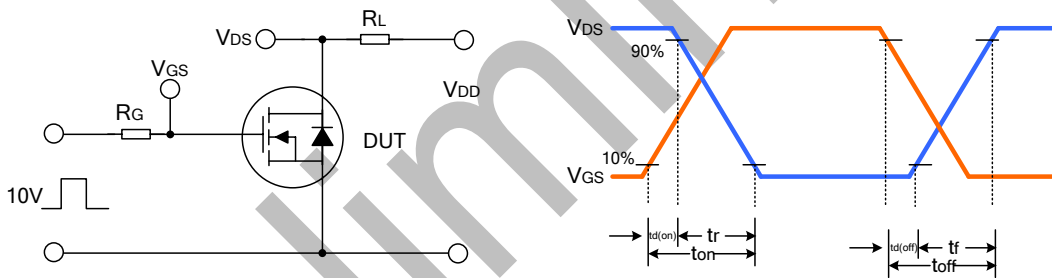
1.  $L=21mH, I_{AS}=9.0A, V_{DD}=50V, R_G=25\Omega,$  starting  $T_J=25^\circ C$ ;
2. Pulse Test: Pulse width  $\leq 300\mu s,$  Duty cycles  $\leq 2\%$ ;
3. Essentially independent of operating temperature.

**TYPICAL TEST CIRCUIT**

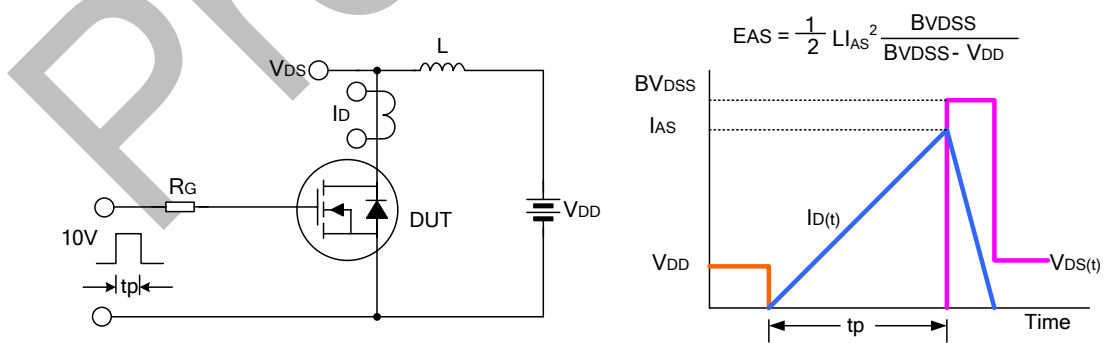
Gate Charge Test Circuit & Waveform



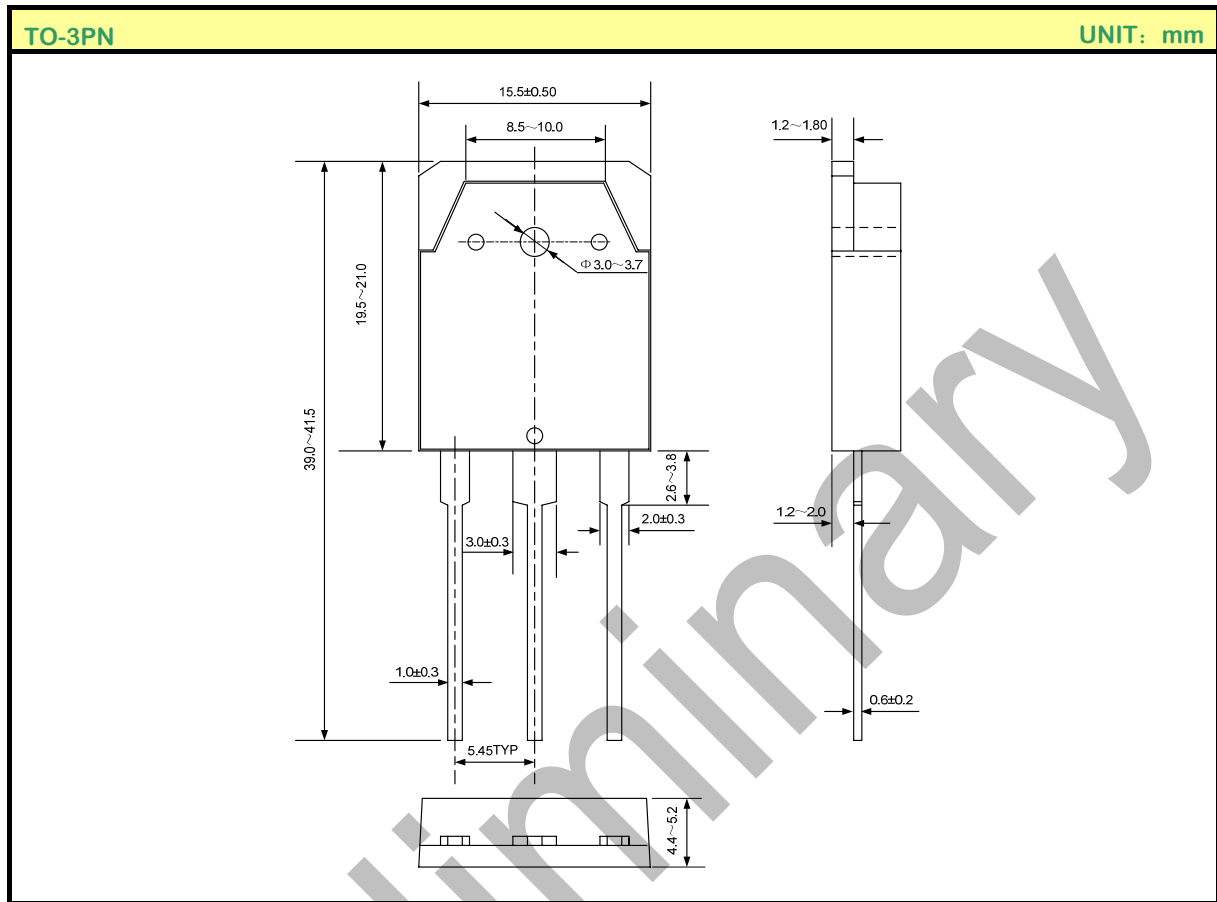
Switching Test Circuit & Waveform



EAS Test Circuit & Waveform



**PACKAGE OUTLINE**



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